

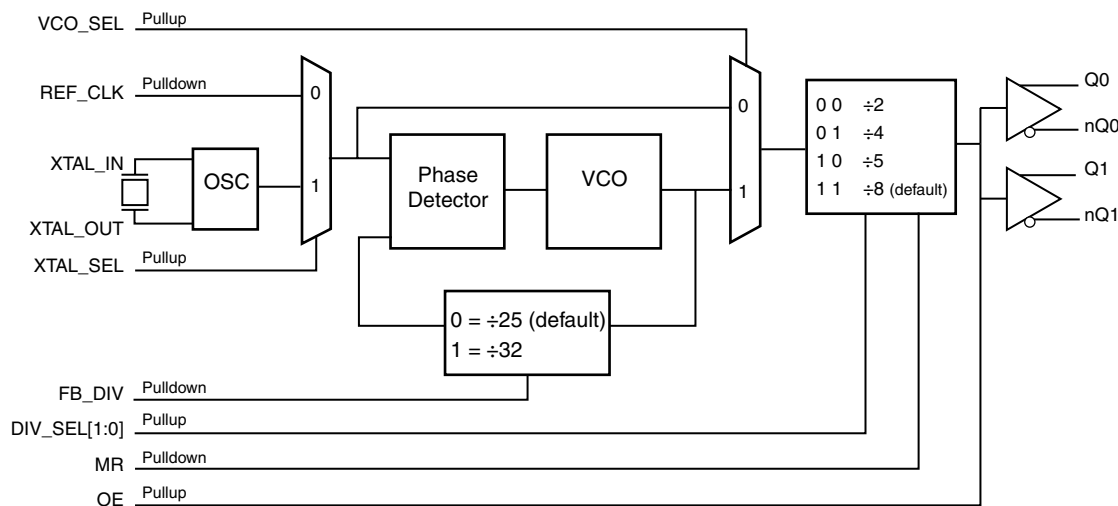
General Description

The ICS844003EI-01 is a 2 differential output LVDS Synthesizer designed to generate Ethernet reference clock frequencies. Using a 19.53125MHz or 25MHz, 18pF parallel resonant crystal, the following frequencies can be generated based on the settings of 2 frequency select pins DIV_SEL[1:0]: 312.5MHz, 156.25MHz, and 125MHz. The ICS844003EI-01 is packaged in a small 24-pin TSSOP package.

Features

- Two LVDS output pairs
- Using a 19.53125MHz or 25MHz crystal, the outputs can be set for 312.5MHz, 156.25MHz or 125MHz
- Selectable crystal oscillator interface or LVCMOS/LVTTL single-ended input
- VCO range: 490MHz - 680MHz
- RMS phase jitter @ 156.25MHz, (1.875MHz - 20MHz): 0.37ps (typical)
- Full 3.3V supply mode
- -40°C to 85°C ambient operating temperature
- Available in lead-free (RoHS 6) package

Block Diagram



Pin Assignment

DIV_SEL0	1	24	DIV_SEL1
VCO_SEL	2	23	VDDO
MR	3	22	Q0
nc	4	21	nQ0
nc	5	20	Q1
nc	6	19	nQ1
OE	7	18	XTAL_SEL
nc	8	17	REF_CLK
FB_DIV	9	16	XTAL_IN
VDDA	10	15	XTAL_OUT
VDD	11	14	GND
nc	12	13	nc

ICS844003EI-01
24-Lead TSSOP
4.4mm x 7.8mm x 0.92mm
package body
G Package
Top View

Table 1. Pin Descriptions

Number	Name	Type		Description
1, 24	DIV_SELO, DIV_SEL1	Input	Pullup	Divide select pin for LVDS outputs. Default = HIGH. See Table 3B. LVCMOS/LVTTL interface levels.
2	VCO_SEL	Input	Pullup	VCO select pin. When Low, the PLL is bypassed and the crystal reference or REF_CLK (depending on XTAL_SEL setting) are passed directly to the output dividers. LVCMOS/LVTTL interface levels.
3	MR	Input	Pulldown	Active HIGH Master Reset. When logic HIGH, the internal dividers are reset causing the true outputs Qx to go low and the inverted outputs nQx to go high. When logic LOW, the internal dividers and the outputs are enabled. LVCMOS/LVTTL interface levels.
4, 5, 6, 8, 12, 13	nc	Unused		No connect.
7	OE	Input	Pullup	Output enable pin. When logic HIGH, the output pairs are enabled. When logic LOW, the output pairs are in a high impedance state. See Table 3D. LVCMOS/LVTTL interface levels.
9	FB_DIV	Input	Pulldown	Feedback divide select. See Table 3C. LVCMOS/LVTTL interface levels.
10	V _{DDA}	Power		Analog supply pin.
11	V _{DD}	Power		Core supply pin.
14	GND	Power		Power supply ground.
15, 16	XTAL_OUT, XTAL_IN	Input		Crystal oscillator interface. XTAL_OUT is the output, XTAL_IN is the input.
17	REF_CLK	Input	Pulldown	Single-ended reference clock input. LVCMOS/LVTTL interface levels.
18	XTAL_SEL	Input	Pullup	Selects between crystal or REF_CLK input. When HIGH, selects XTAL inputs. When LOW, selects REF_CLK. LVCMOS/LVTTL interface levels.
19, 20	nQ1, Q1	Output		Differential output pair. LVDS interface levels.
21, 22	nQ0, Q0	Output		Differential output pair. LVDS interface levels.
23	V _{DDO}	Power		Output supply pin.

NOTE: *Pullup* and *Pulldown* refer to internal input resistors. See Table 2, *Pin Characteristics*, for typical values.

Table 2. Pin Characteristics

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
C _{IN}	Input Capacitance			4		pF
R _{PULLDOWN}	Input Pulldown Resistor			51		kΩ
R _{PULLUP}	Input Pullup Resistor			51		kΩ

Function Tables

Table 3A. Frequency Configuration Table

Inputs				Feedback Divider	Output Divider	M/N Multiplication Factor	Q[0, 1], nQ[0, 1] Output Frequency (MHz)
Crystal Frequency (MHz)	FB_DIV	DIV_SEL1	DIV_SEL0				
25	0	0	0	25	2	12.5	312.5
20	0	0	0	25	2	12.5	250
25	0	0	1	25	4	6.25	156.25
24	0	0	1	25	4	6.25	150
20	0	0	1	25	4	6.25	125
25	0	1	0	25	5	5	125
25	0	1	1	25	8	3.125	78.125
24	0	1	1	25	8	3.125	75
20	0	1	1	25	8	3.125	62.5
19.44	1	0	0	32	2	16	311.04
15.625	1	0	0	32	2	16	250
19.44	1	0	1	32	4	8	155.52
18.75	1	0	1	32	4	8	150
15.625	1	0	1	32	4	8	125
15.625	1	1	0	32	5	6.4	100
19.44	1	1	1	32	8	4	77.76
18.75	1	1	1	32	8	4	75
15.625	1	1	1	32	8	4	62.5

Table 3B. Output Configuration Select Function Table

Inputs		Outputs
DIV_SEL1	DIV_SEL0	Q[0, 1], nQ[0, 1]
0	0	÷2
0	1	÷4
1	0	÷5
1	1	÷8 (default)

Table 3C. Feedback Divider Configuration Select Function Table

Input	
FB_DIV	Feedback Divide
0	÷25 (default)
1	÷32

Table 3D. OE Select Function Table

Input	Outputs
OE	Q[0, 1], nQ[0, 1]
0	High-Impedance
1	Active (default)

Absolute Maximum Ratings

NOTE: Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics* or *AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

Item	Rating
Supply Voltage, V_{DD}	4.6V
Inputs, V_I XTAL_IN Other Inputs	0V to V_{DD} -0.5V to $V_{DD} + 0.5V$
Outputs, I_O Continuous Current Surge Current	10mA 15mA
Package Thermal Impedance, θ_{JA}	82.3°C/W (0 mps)
Storage Temperature, T_{STG}	-65°C to 150°C

DC Electrical Characteristics

Table 4A. Power Supply DC Characteristics, $V_{DD} = V_{DDO} = 3.3V \pm 5\%$, $T_A = -40^\circ\text{C}$ to 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V_{DD}	Core Supply Voltage		3.135	3.3	3.465	V
V_{DDA}	Analog Supply Voltage		$V_{DD} - 0.12$	3.3	V_{DD}	V
V_{DDO}	Output Supply Voltage		3.135	3.3	3.465	V
I_{DD}	Power Supply Current				76	mA
I_{DDA}	Analog Supply Current				12	mA
I_{DDO}	Output Supply Current				50	mA

Table 4B. LVCMOS/LVTTL DC Characteristics, $V_{DD} = V_{DDO} = 3.3V \pm 5\%$, $T_A = -40^\circ\text{C}$ to 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V_{IH}	Input High Voltage	$V_{DD} = 3.3V$	2		$V_{DD} + 0.3$	V
V_{IL}	Input Low Voltage	$V_{DD} = 3.3V$	-0.3		0.8	V
I_{IH}	Input High Current	MR, REF_CLK, FB_DIV $V_{DD} = V_{IN} = 3.465V$			150	μA
		OE, DIV_SEL[0:1], VCO_SEL, XTAL_SEL $V_{DD} = V_{IN} = 3.465V$			5	μA
I_{IL}	Input Low Current	MR, REF_CLK, FB_DIV $V_{DD} = 3.465V, V_{IN} = 0V$	-5			μA
		OE, DIV_SEL[0:1], VCO_SEL, XTAL_SEL $V_{DD} = 3.465V, V_{IN} = 0V$	-150			μA

Table 4C. LVDS DC Characteristics, $V_{DD} = V_{DDO} = 3.3V \pm 5\%$, $T_A = -40^\circ\text{C}$ to 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V_{OD}	Differential Output Voltage		300		500	mV
ΔV_{OD}	V_{OD} Magnitude Change				50	mV
V_{OS}	Offset Voltage		1.15		1.55	V
ΔV_{OS}	V_{OS} Magnitude Change				50	mV

Table 5. Crystal Characteristics

Parameter	Test Conditions	Minimum	Typical	Maximum	Units
Mode of Oscillation		Fundamental			
Frequency	FB_DIV = ± 25	19.6		27.2	MHz
	FB_DIV = ± 32	15.313		21.25	MHz
Equivalent Series Resistance (ESR)				50	Ω
Shunt Capacitance				7	pF

NOTE: Characterized using an 18pF parallel resonant crystal.

AC Electrical Characteristics

Table 6. AC Characteristics, $V_{DD} = V_{DDO} = 3.3V \pm 5\%$, $T_A = -40^\circ\text{C}$ to 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
f_{OUT}	Output Frequency	DIV_SEL[1:0] = 00	245		340	MHz
		DIV_SEL[1:0] = 01	122.5		170	MHz
		DIV_SEL[1:0] = 10	98		136	MHz
		DIV_SEL[1:0] = 11	61.25		85	MHz
$t_{sk(o)}$	Output Skew; NOTE 1, 2				30	ps
$\sigma_{jit}(\emptyset)$	RMS Phase Jitter (Random); NOTE 3	312.5MHz, (1.875MHz – 20MHz)		0.33		ps
		156.25MHz, (1.875MHz – 20MHz)		0.37		ps
		125MHz, (1.875MHz – 20MHz)		0.37		ps
t_R / t_F	Output Rise/Fall Time	20% to 80%	200		525	ps
odc	Output Duty Cycle		46		54	%

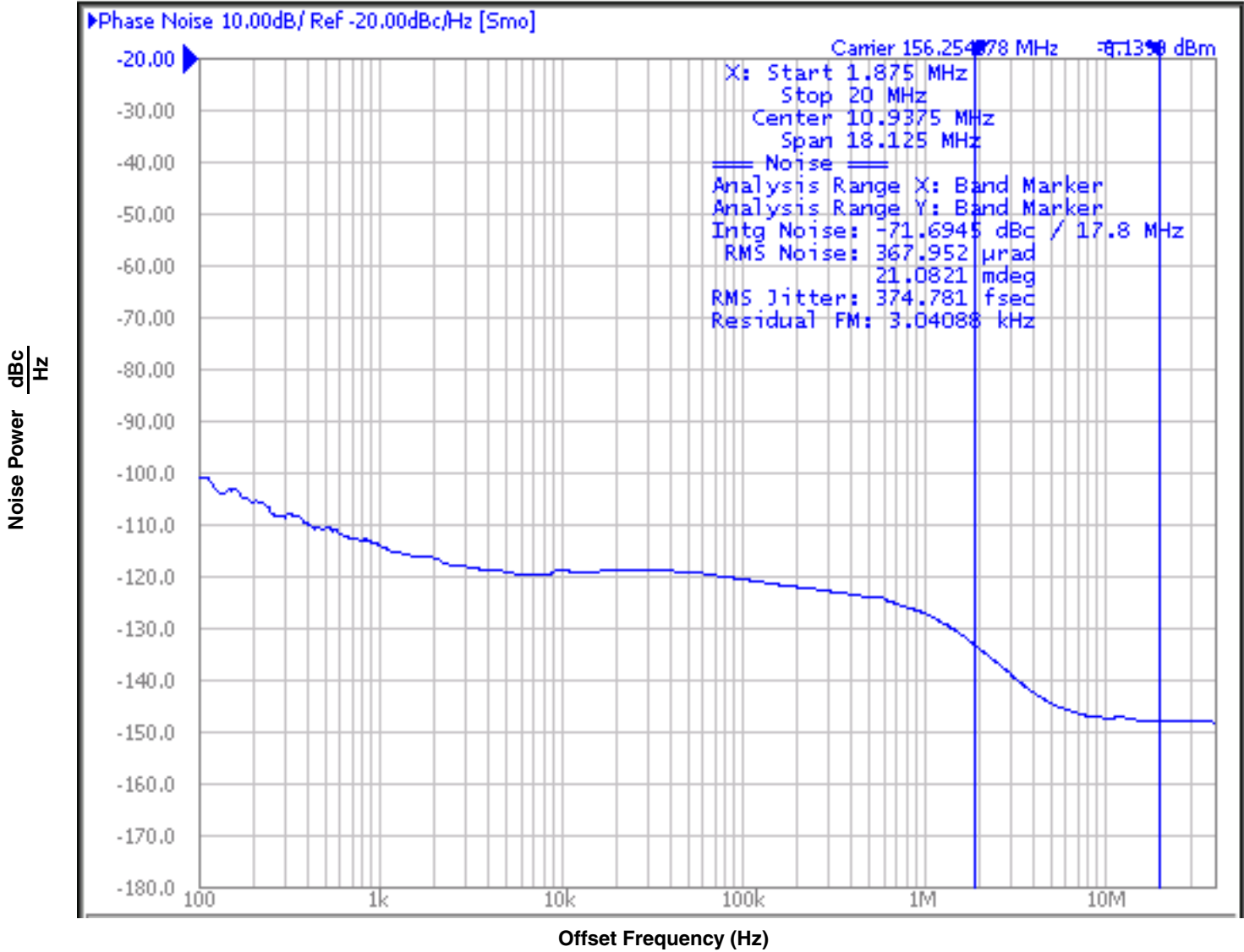
NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lfm. The device will meet specifications after thermal equilibrium has been reached under these conditions.

NOTE 1: Defined as skew between outputs at the same supply voltage and with equal load conditions. Measured at the differential cross points.

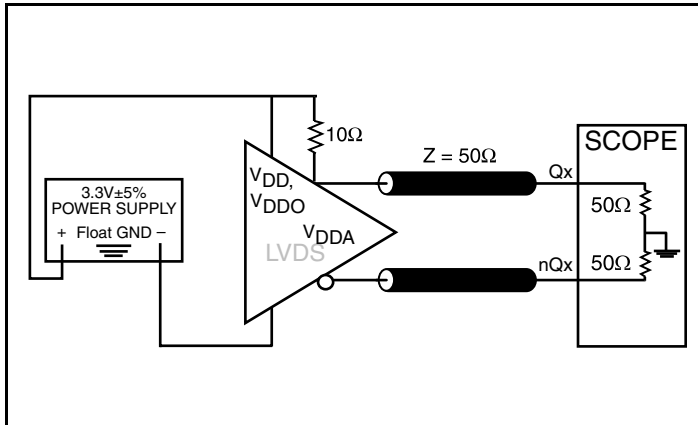
NOTE 2: This parameter is defined in accordance with JEDEC Standard 65.

NOTE 3: Please refer to the Phase Noise Plot.

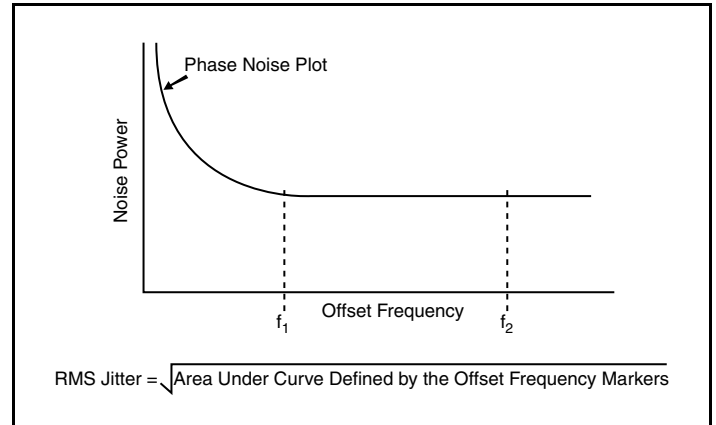
Typical Phase Noise at 156.25MHz



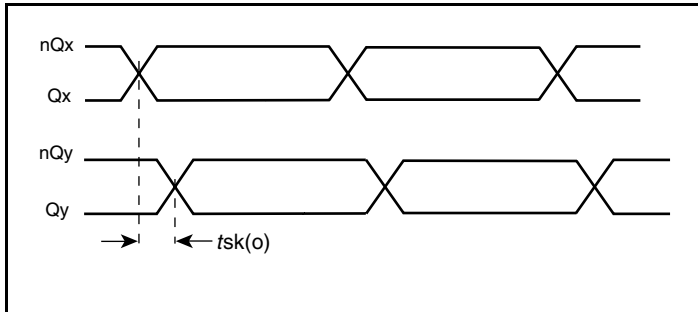
Parameter Measurement Information



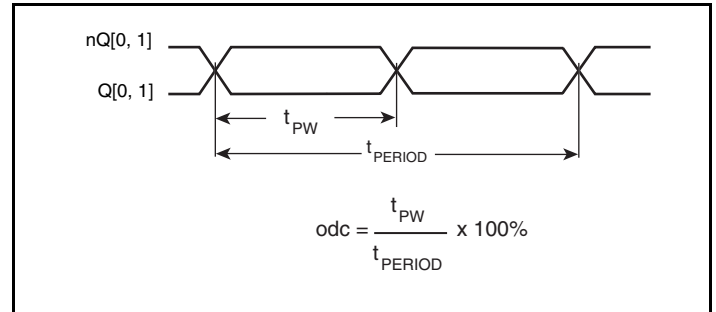
Output Load AC Test Circuit



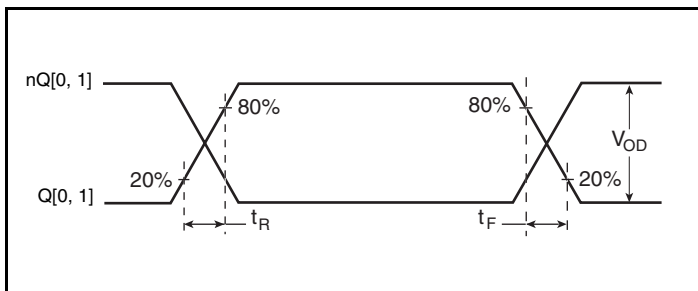
RMS Phase Jitter



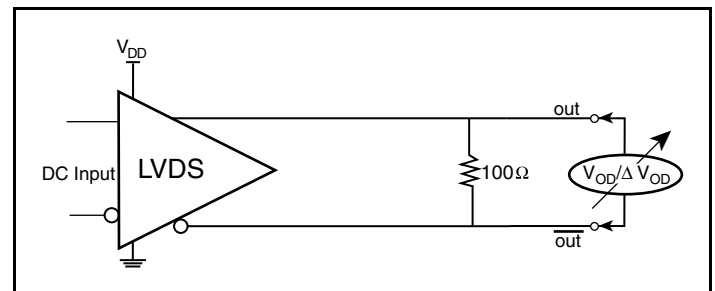
Output Skew



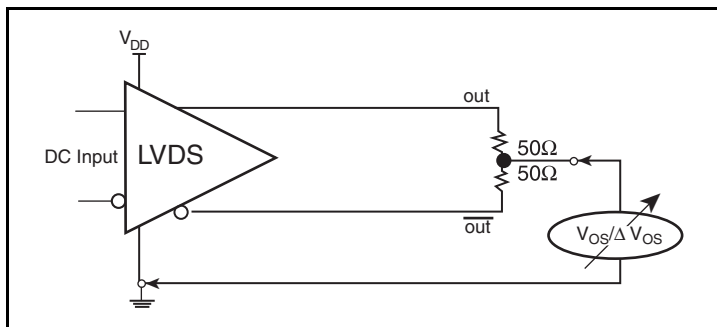
Output Duty Cycle/Pulse Width/Period



Output Rise/Fall Time



Differential Output Voltage Setup



Offset Voltage Setup

Applications Information

Power Supply Filtering Technique

As in any high speed analog circuitry, the power supply pins are vulnerable to random noise. To achieve optimum jitter performance, power supply isolation is required. The ICS844003EI-01 provides separate power supplies to isolate any high switching noise from the outputs to the internal PLL. V_{DD} , V_{DDA} and V_{DDO} should be individually connected to the power supply plane through vias, and $0.01\mu\text{F}$ bypass capacitors should be used for each pin. *Figure 1* illustrates this for a generic V_{DD} pin and also shows that V_{DDA} requires that an additional 10Ω resistor along with a $10\mu\text{F}$ bypass capacitor be connected to the V_{DDA} pin.

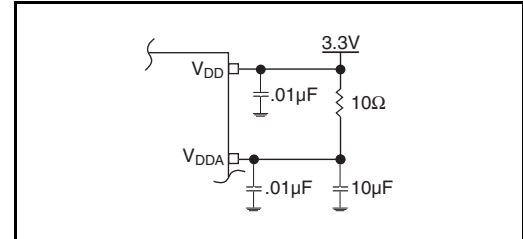


Figure 1. Power Supply Filtering

Recommendations for Unused Input and Output Pins

Inputs:

LVCMOS Control Pins

All control pins have internal pullups and pulldowns; additional resistance is not required but can be added for additional protection. A $1\text{k}\Omega$ resistor can be used.

Crystal Inputs

For applications not requiring the use of the crystal oscillator input, both XTAL_IN and XTAL_OUT can be left floating. Though not required, but for additional protection, a $1\text{k}\Omega$ resistor can be tied from XTAL_IN to ground.

REF_CLK Input

For applications not requiring the use of the reference clock, it can be left floating. Though not required, but for additional protection, a $1\text{k}\Omega$ resistor can be tied from the REF_CLK to ground.

Outputs:

LVDS Outputs

All unused LVDS output pairs can be either left floating or terminated with 100Ω across. If they are left floating, there should be no trace attached.

Crystal Input Interface

The ICS844003EI-01 has been characterized with 18pF parallel resonant crystals. The capacitor values shown in *Figure 2* below were determined using a 19.53125MHz or 25MHz, 18pF parallel resonant crystal and were chosen to minimize the ppm error.

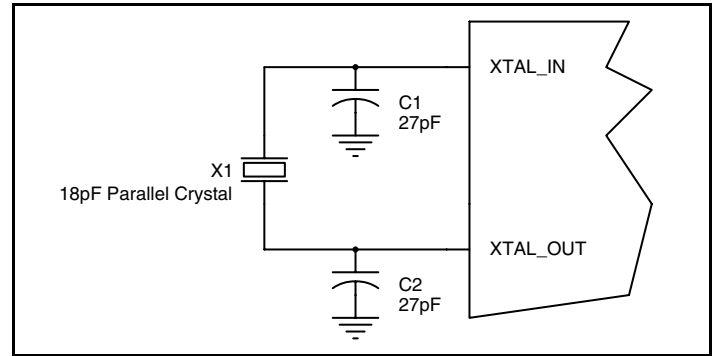


Figure 2. Crystal Input Interface

Overdriving the XTAL Interface

The XTAL_IN input can accept a single-ended LVCMOS signal through an AC coupling capacitor. A general interface diagram is shown in *Figure 3A*. The XTAL_OUT pin can be left floating. The maximum amplitude of the input signal should not exceed 2V and the input edge rate can be as slow as 10ns. This configuration requires that the output impedance of the driver (R_o) plus the series resistance (R_s) equals the transmission line impedance. In addition,

matched termination at the crystal input will attenuate the signal in half. This can be done in one of two ways. First, R_1 and R_2 in parallel should equal the transmission line impedance. For most 50 Ω applications, R_1 and R_2 can be 100 Ω . This can also be accomplished by removing R_1 and making R_2 50 Ω . By overdriving the crystal oscillator, the device will be functional, but note, the device performance is guaranteed by using a quartz crystal.

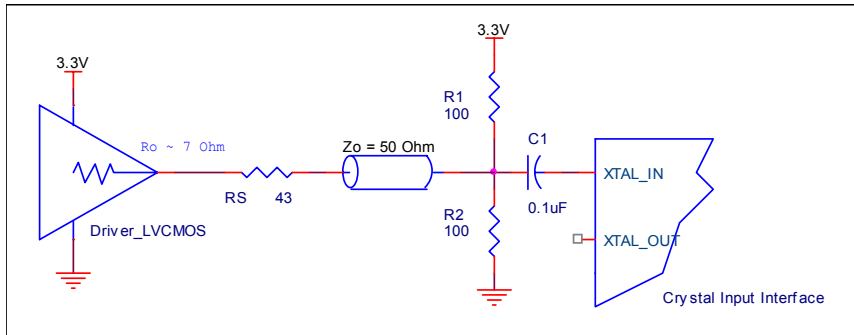


Figure 3A. General Diagram for LVCMOS Driver to XTAL Input Interface

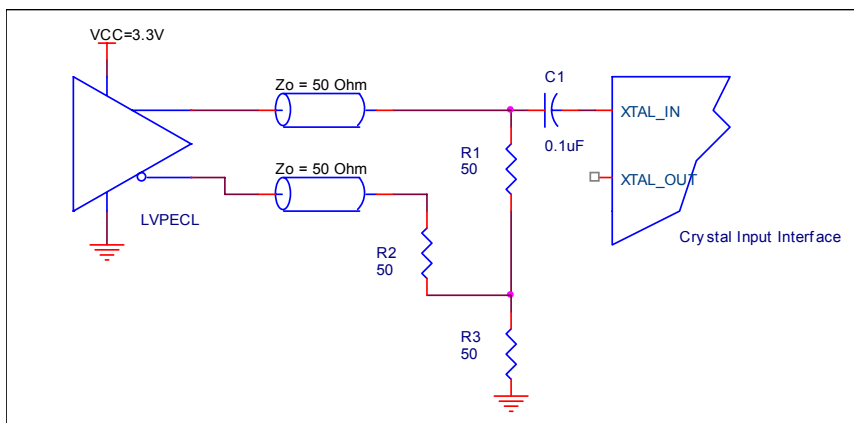


Figure 3B. General Diagram for LVPECL Driver to XTAL Input Interface

LVDS Driver Termination

A general LVDS interface is shown in *Figure 4*. Standard termination for LVDS type output structure requires both a 100Ω parallel resistor at the receiver and a 100Ω differential transmission line environment. In order to avoid any transmission line reflection issues, the 100Ω resistor must be placed as close to the receiver as possible. IDT offers a full line of LVDS compliant devices with two types of output structures: current source and voltage source. The standard

termination schematic as shown in Figure 4 can be used with either type of output structure. If using a non-standard termination, it is recommended to contact IDT and confirm if the output is a current source or a voltage source type structure. In addition, since these outputs are LVDS compatible, the amplitude and common mode input range of the input receivers should be verified for compatibility with the output.

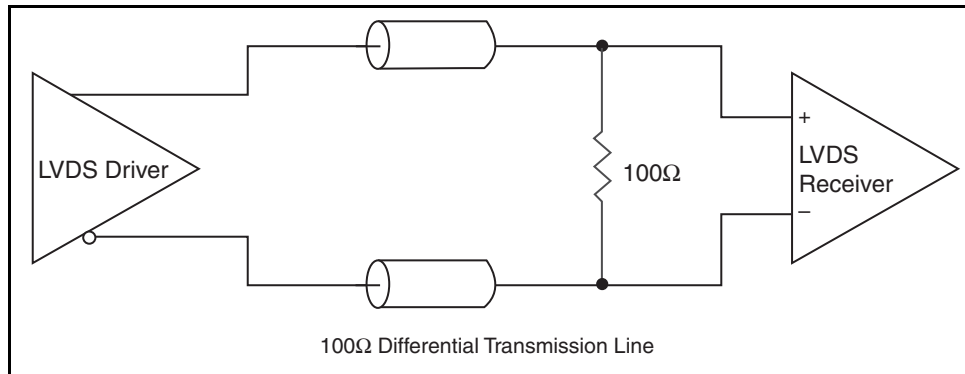


Figure 4. Typical LVDS Driver Termination

Schematic Example

Figure 5 shows an example of ICS844003EI-01 application schematic. In this example, the device is operated at $V_{DD} = V_{DDO} = 3.3V$. The 18pF parallel resonant 25MHz crystal is used. The C1= 27pF and C2 = 27pF are recommended for frequency accuracy. For

different board layouts, the C1 and C2 may be slightly adjusted for optimizing frequency accuracy. Two examples of LVDS for receiver without built-in termination are shown in this schematic.

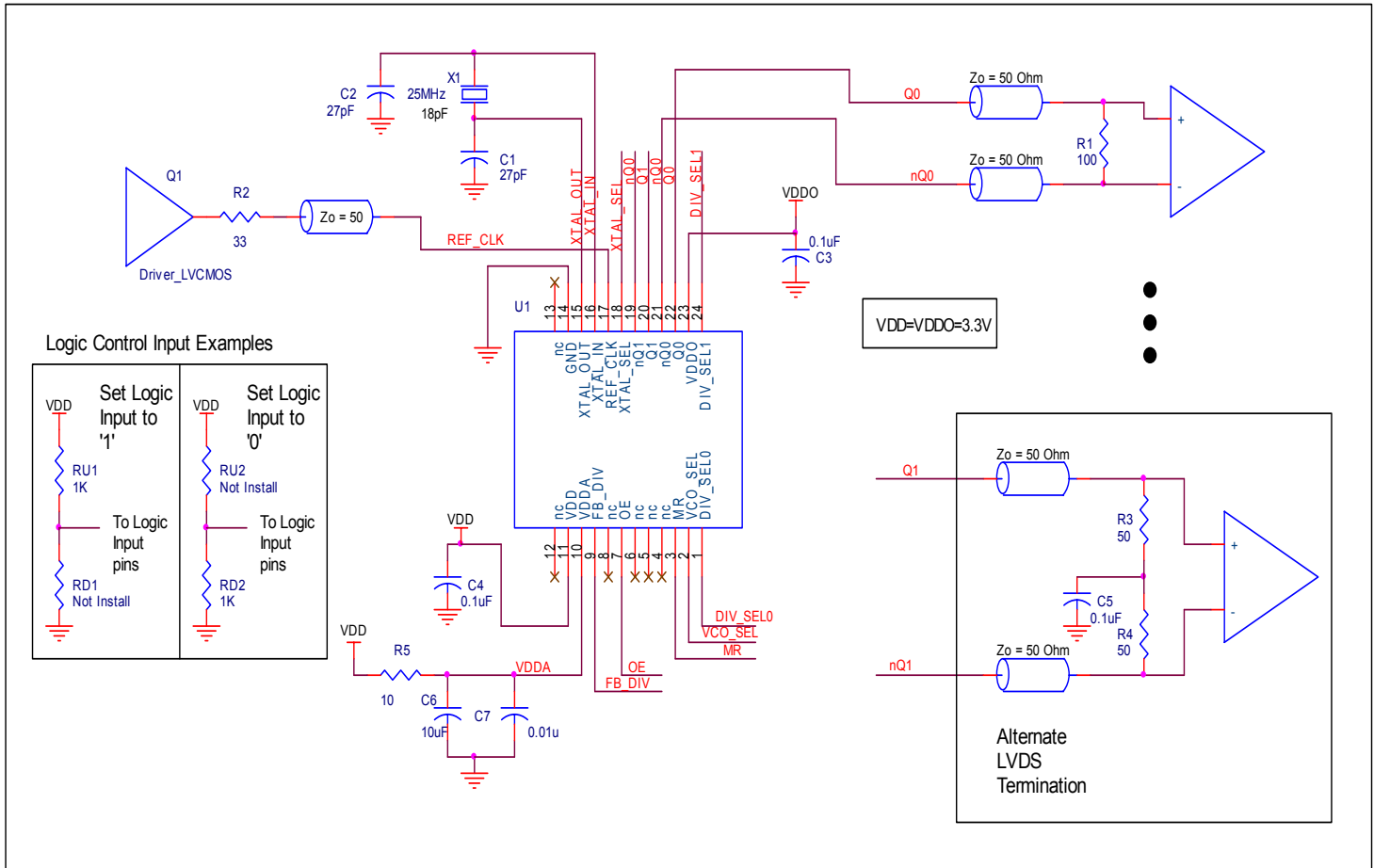


Figure 5. ICS844003EI-01 Schematic Layout Example

Power Considerations

This section provides information on power dissipation and junction temperature for the ICS844003EI-01. Equations and example calculations are also provided.

1. Power Dissipation.

The total power dissipation for the ICS844003EI-01 is the sum of the core power plus the analog power plus the power dissipated in the load(s). The following is the power dissipation for $V_{DD} = 3.3V + 5\% = 3.465V$, which gives worst case results.

- Power (core)_{MAX} = $V_{DD_MAX} * (I_{DD_MAX} + I_{DDA_MAX}) = 3.465V * (76mA + 12mA) = \mathbf{305mW}$
- Power (outputs)_{MAX} = $V_{DDO_MAX} * I_{DDO_MAX} = 3.465V * 50mA = \mathbf{173mW}$

Total Power_{MAX} = 305mW + 173mW = **478mW**

2. Junction Temperature.

Junction temperature, T_j , is the temperature at the junction of the bond wire and bond pad directly affects the reliability of the device. The maximum recommended junction temperature is 125°C. Limiting the internal transistor junction temperature, T_j , to 125°C ensures that the bond wire and bond pad temperature remains below 125°C.

The equation for T_j is as follows: $T_j = \theta_{JA} * Pd_total + T_A$

T_j = Junction Temperature

θ_{JA} = Junction-to-Ambient Thermal Resistance

Pd_total = Total Device Power Dissipation (example calculation is in section 1 above)

T_A = Ambient Temperature

In order to calculate junction temperature, the appropriate junction-to-ambient thermal resistance θ_{JA} must be used. Assuming no air flow and a multi-layer board, the appropriate value is 82.3°C/W per Table 7 below.

Therefore, T_j for an ambient temperature of 85°C with all outputs switching is:

$$85^\circ\text{C} + 0.478\text{W} * 82.3^\circ\text{C/W} = 124.3^\circ\text{C}. \text{ This is below the limit of } 125^\circ\text{C}.$$

This calculation is only an example. T_j will obviously vary depending on the number of loaded outputs, supply voltage, air flow and the type of board (multi-layer).

Table 7. Thermal Resistance θ_{JA} for 24 Lead TSSOP, Forced Convection

θ_{JA} by Velocity			
Meters per Second	0	1	2.5
Multi-Layer PCB, JEDEC Standard Test Boards	82.3°C/W	78.0°C/W	75.9°C/W

Reliability Information

Table 8. θ_{JA} vs. Air Flow Table for a 24 Lead TSSOP

θ_{JA} by Velocity			
Meters per Second	0	1	2.5
Multi-Layer PCB, JEDEC Standard Test Boards	82.3°C/W	78.0°C/W	75.9°C/W

Transistor Count

The transistor count for ICS844003EI-01 is: 2621

Package Outline and Package Dimensions

Package Outline - G Suffix for 24 Lead TSSOP

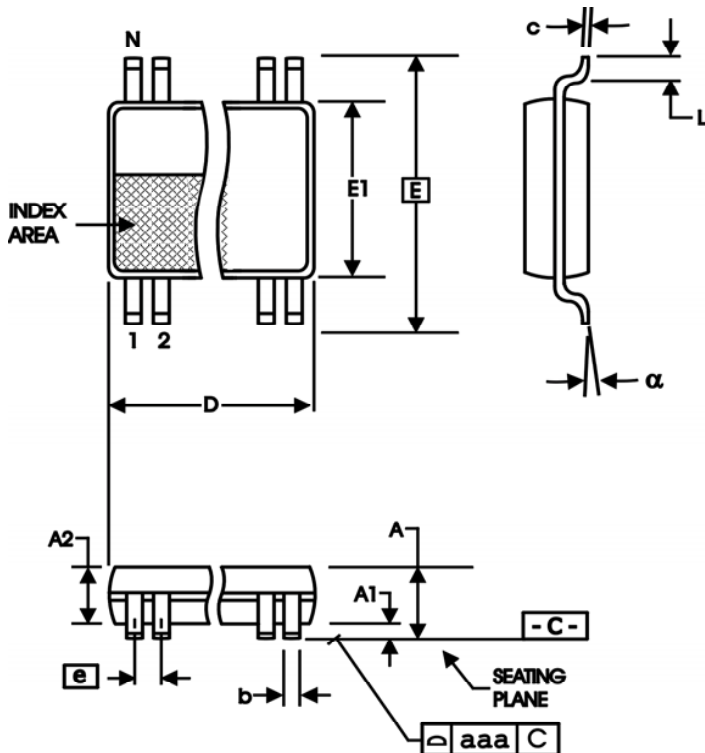


Table 9. Package Dimensions

All Dimensions in Millimeters		
Symbol	Minimum	Maximum
N	24	
A		1.20
A1	0.5	0.15
A2	0.80	1.05
b	0.19	0.30
c	0.09	0.20
D	7.70	7.90
E	6.40 Basic	
E1	4.30	4.50
e	0.65 Basic	
L	0.45	0.75
α	0°	8°
aaa		0.10

Reference Document: JEDEC Publication 95, MO-153

Ordering Information

Table 10. Ordering Information

Part/Order Number	Marking	Package	Shipping Packaging	Temperature
844003EGI-01LF	ICS44003EI01L	“Lead-Free” 24 Lead TSSOP	Tube	-40°C to 85°C
844003EGI-01LFT	ICS44003EI01L	“Lead-Free” 24 Lead TSSOP	2500 Tape & Reel	-40°C to 85°C

NOTE: Parts that are ordered with an "LF" suffix to the part number are the Pb-Free configuration and are RoHS compliant.

While the information presented herein has been checked for both accuracy and reliability, Integrated Device Technology (IDT) assumes no responsibility for either its use or for the infringement of any patents or other rights of third parties, which would result from its use. No other circuits, patents, or licenses are implied. This product is intended for use in normal commercial and industrial applications. Any other applications, such as those requiring high reliability or other extraordinary environmental requirements are not recommended without additional processing by IDT. IDT reserves the right to change any circuitry or specifications without notice. IDT does not authorize or warrant any IDT product for use in life support devices or critical medical instruments.

We've Got Your Timing Solution



6024 Silver Creek Valley Road
San Jose, California 95138

Sales

800-345-7015 (inside USA)
+408-284-8200 (outside USA)
Fax: 408-284-2775
www.IDT.com/go/contactIDT

Technical Support

netcom@idt.com
+480-763-2056

DISCLAIMER Integrated Device Technology, Inc. (IDT) and its subsidiaries reserve the right to modify the products and/or specifications described herein at any time and at IDT's sole discretion. All information in this document, including descriptions of product features and performance, is subject to change without notice. Performance specifications and the operating parameters of the described products are determined in the independent state and are not guaranteed to perform the same way when installed in customer products. The information contained herein is provided without representation or warranty of any kind, whether express or implied, including, but not limited to, the suitability of IDT's products for any particular purpose, an implied warranty of merchantability, or non-infringement of the intellectual property rights of others. This document is presented only as a guide and does not convey any license under intellectual property rights of IDT or any third parties.

IDT's products are not intended for use in life support systems or similar devices where the failure or malfunction of an IDT product can be reasonably expected to significantly affect the health or safety of users. Anyone using an IDT product in such a manner does so at their own risk, absent an express, written agreement by IDT.

Integrated Device Technology, IDT and the IDT logo are registered trademarks of IDT. Other trademarks and service marks used herein, including protected names, logos and designs, are the property of IDT or their respective third party owners.

Copyright 2010. All rights reserved.